

Voiding: Contrary Effects of Voiding

APEX Conference & Exhibition, San Diego

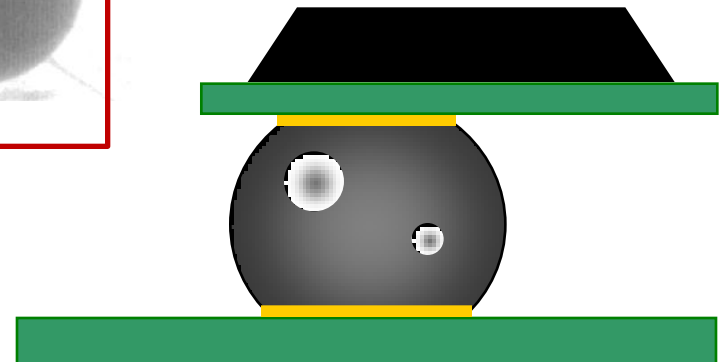
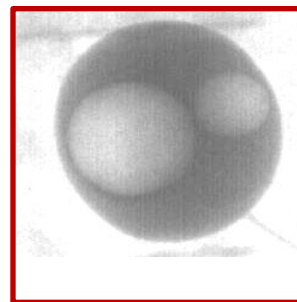
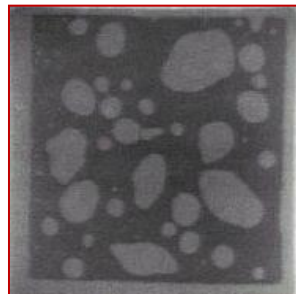
February 20th, 2013

Dr. Hans Bell, Helmut Öttl, Dr. Heinz Wohlrabe

Voiding

■ Contrary effects - BGA versus BTC solder joints

- BTC/area solder joints require **good** wetting to achieve low voiding
- BGA solder joints show better results with **bad** wetting
- BTC/area solder joints usually have undefined void shapes
- BGA solder joints usually have spherical pores



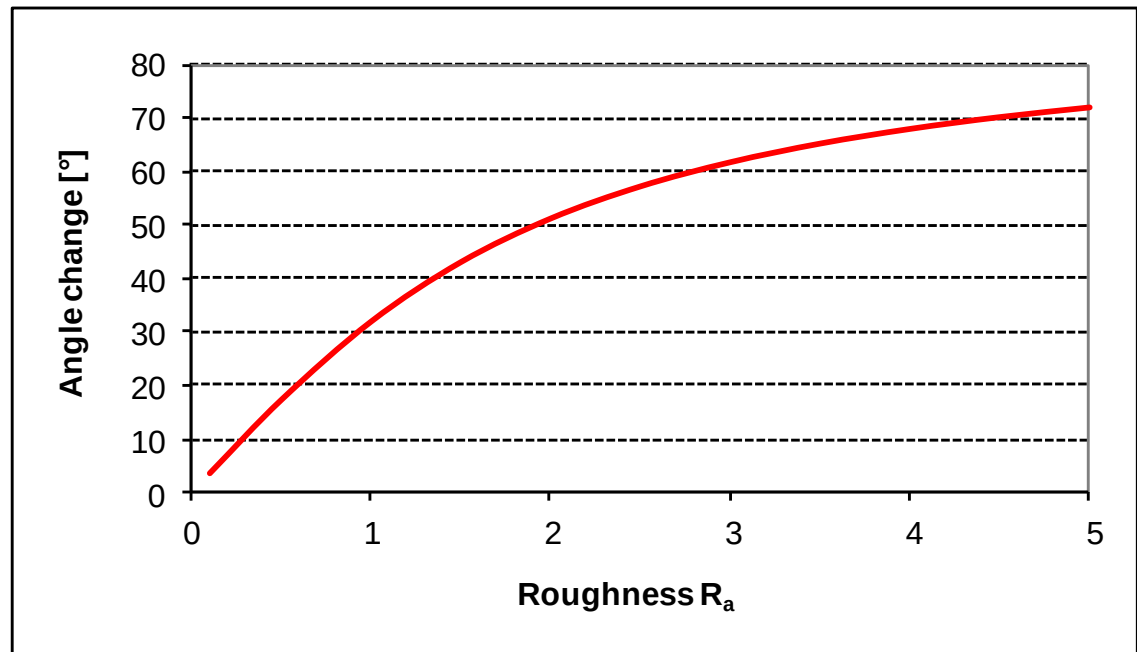
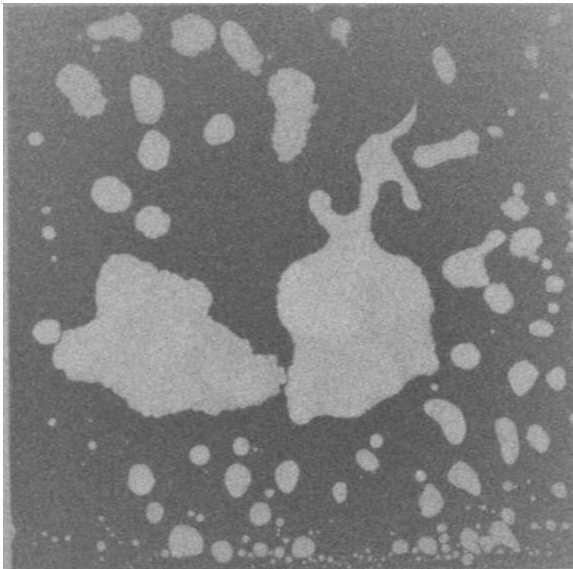
Voiding

■ Void shape

■ Influence of roughness on the wetting angle θ

$$\tan \alpha = \frac{R_a}{\lambda} \cdot \pi$$

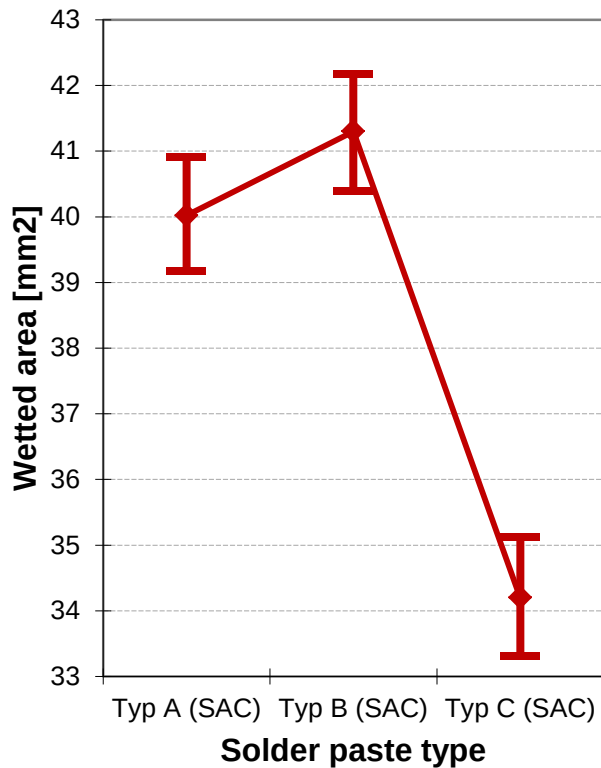
$$\theta_a = \theta + \alpha, \quad \theta_r = \theta - \alpha$$



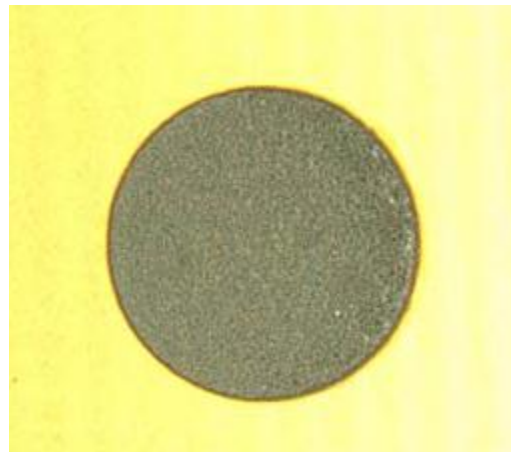
Voiding

■ Influence of solder paste and wetting

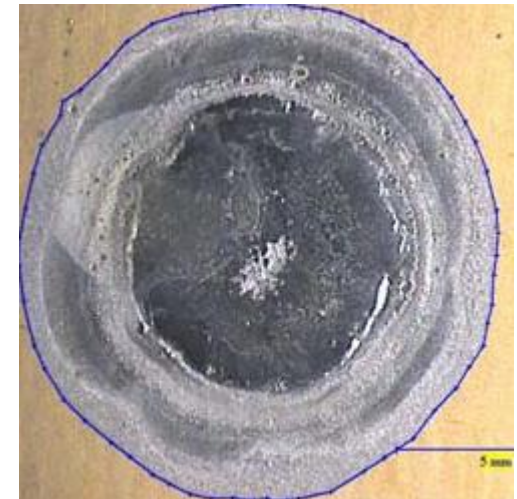
■ Solder spreading



Paste deposit



Wetted area

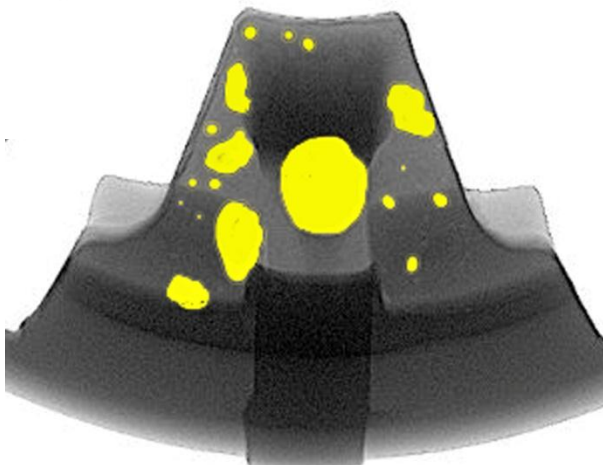


Voiding

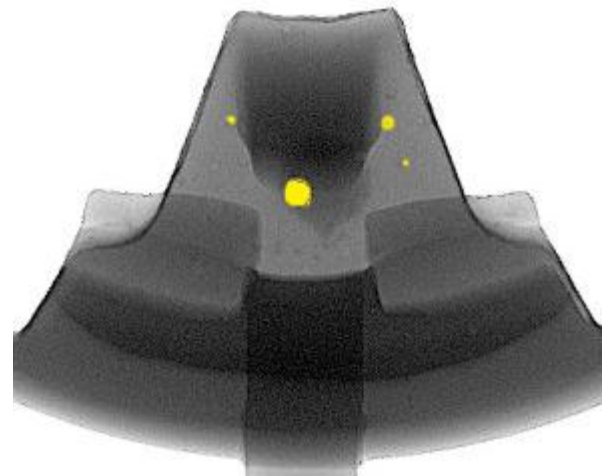
■ Influence of wetting

- Copper contact, SAC solder

As delivered, no cleaning



Chemical cleaning before soldering

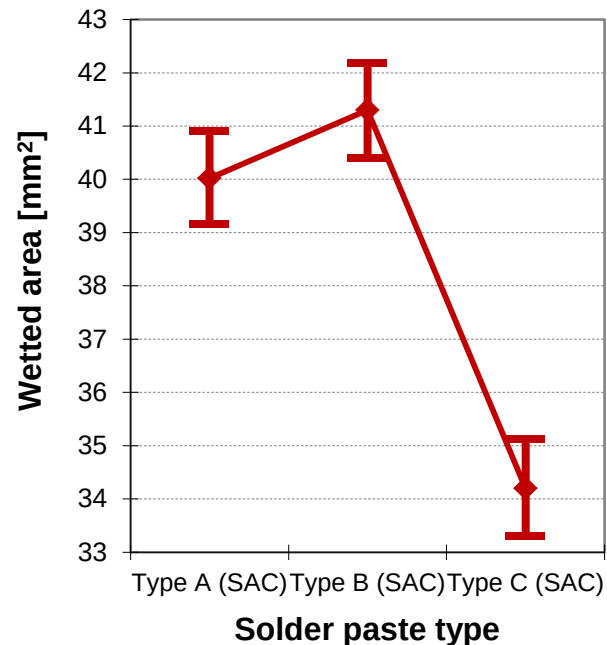


Voiding

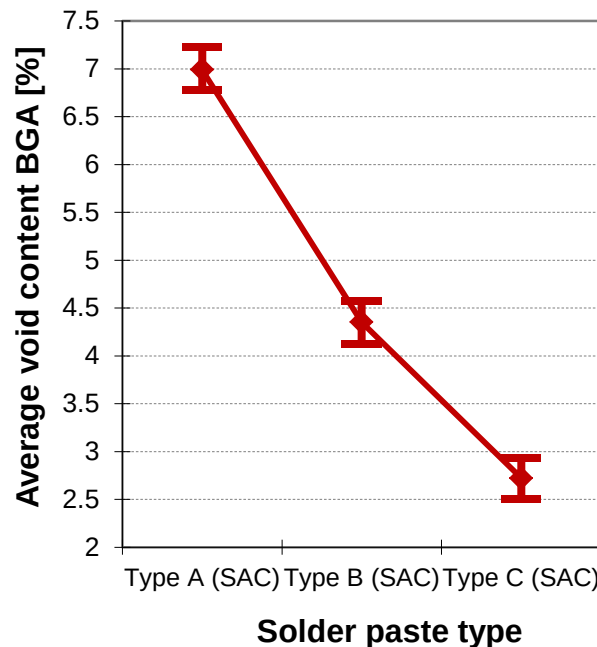
■ Influence of solder paste and wetting

- Contrary effects, BGA vs. Si-Chip solder joints

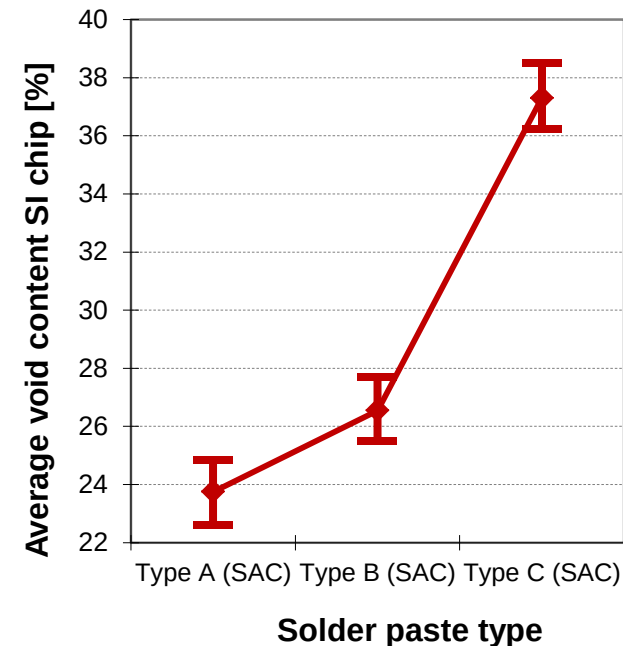
Solder spreading



BGA 176



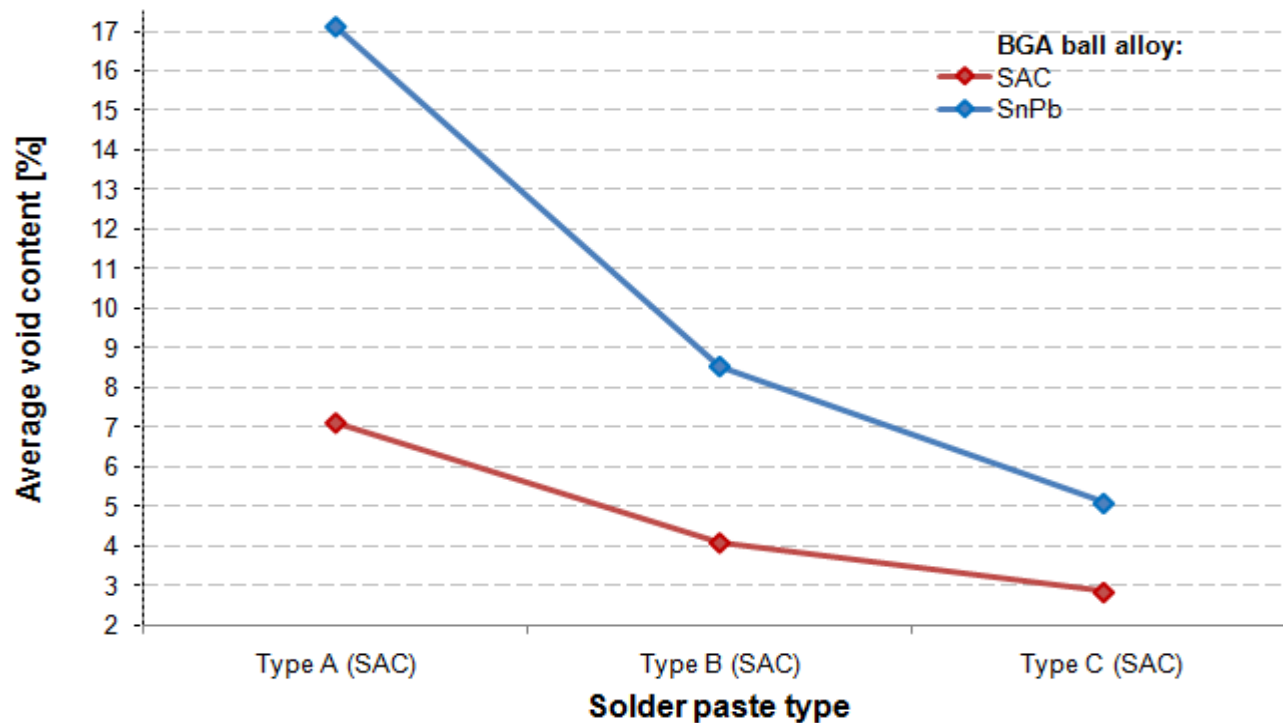
Si Chip



Voiding

■ Influence of alloy

- SAC solder paste, BGA: SnPb balls vs. SAC balls

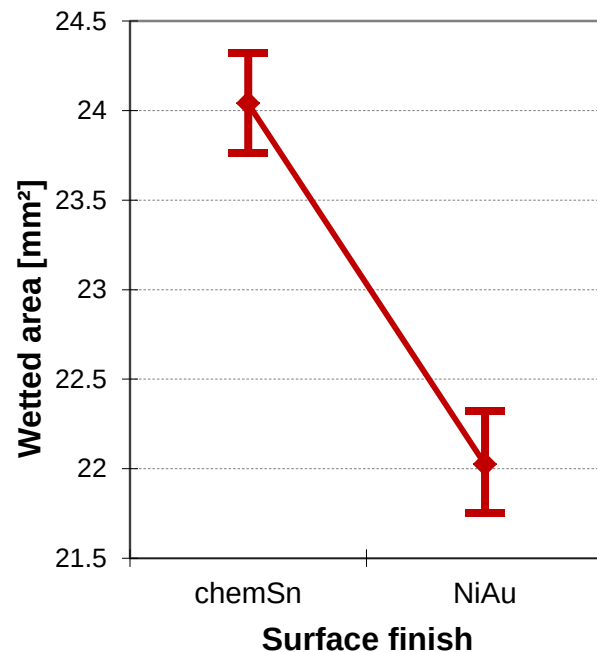


Source: Heinz Wohlrabe, VoidExpert Database, 2013

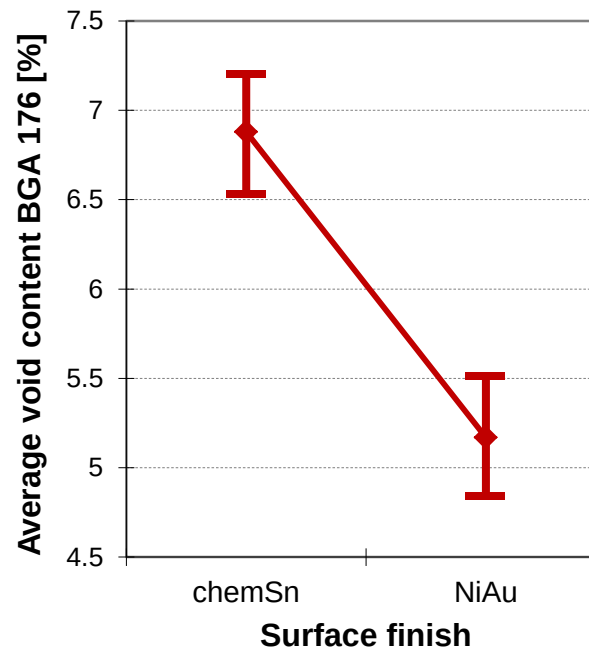
Voiding

- **Influence of surface finish and wetting**
 - Contrary effects, BGA vs. QFN solder joints

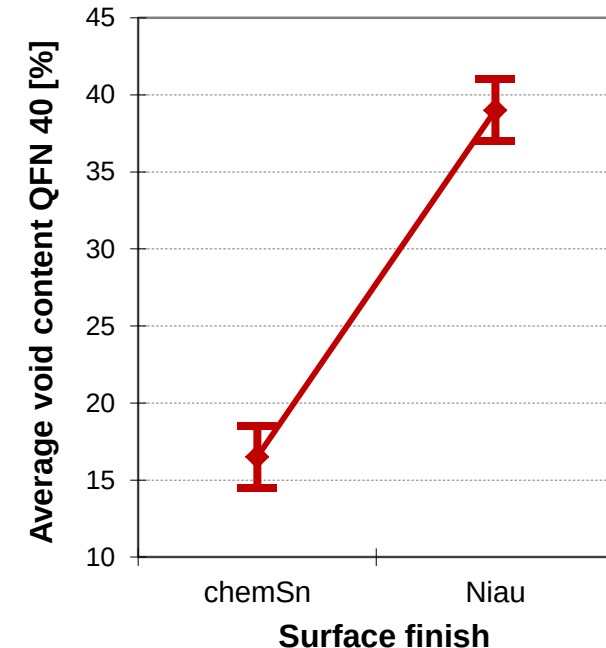
Solder spreading



BGA 176



QFN 40

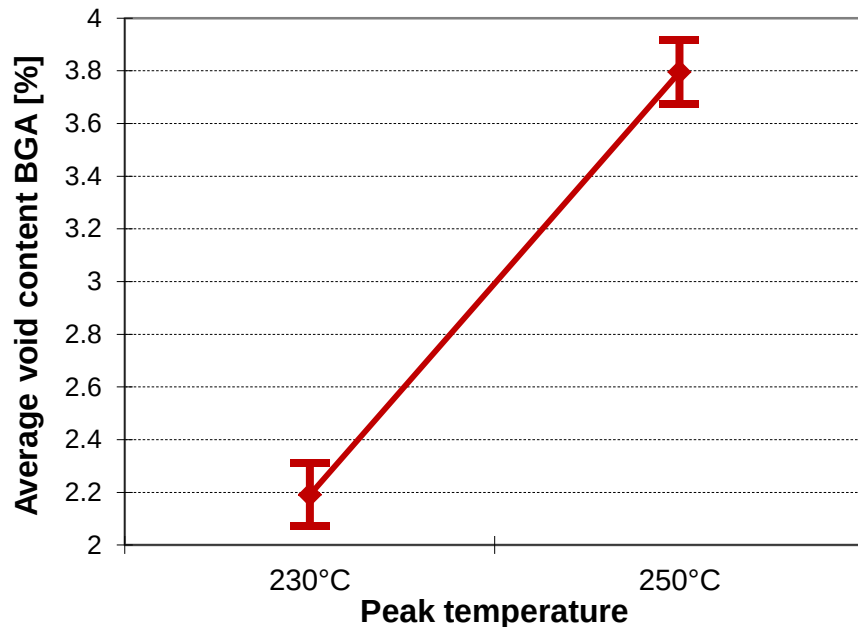


Voiding

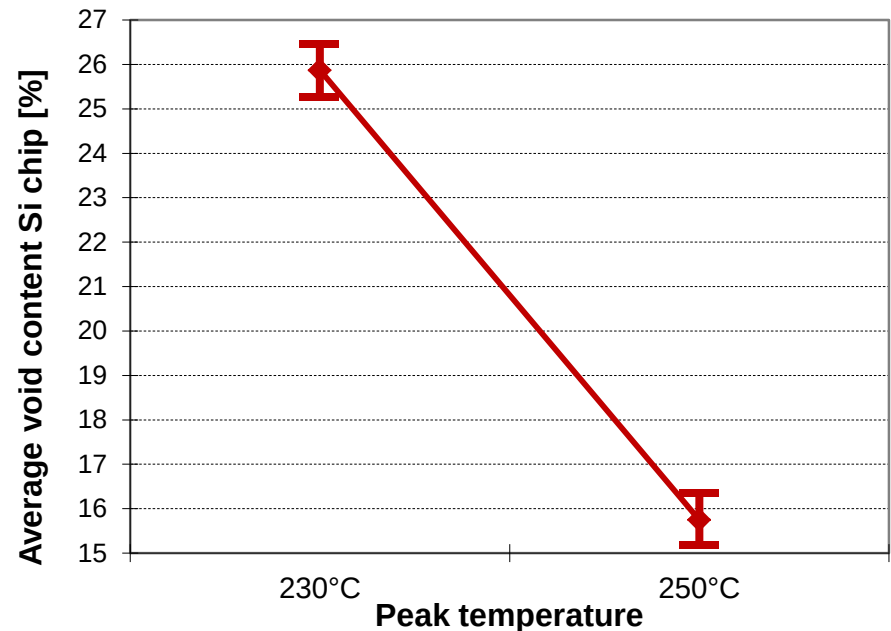
■ Influence of peak temperature

- Contrary effects, BGA vs. Si chip soldering joints

BGA 196



Si-Chip

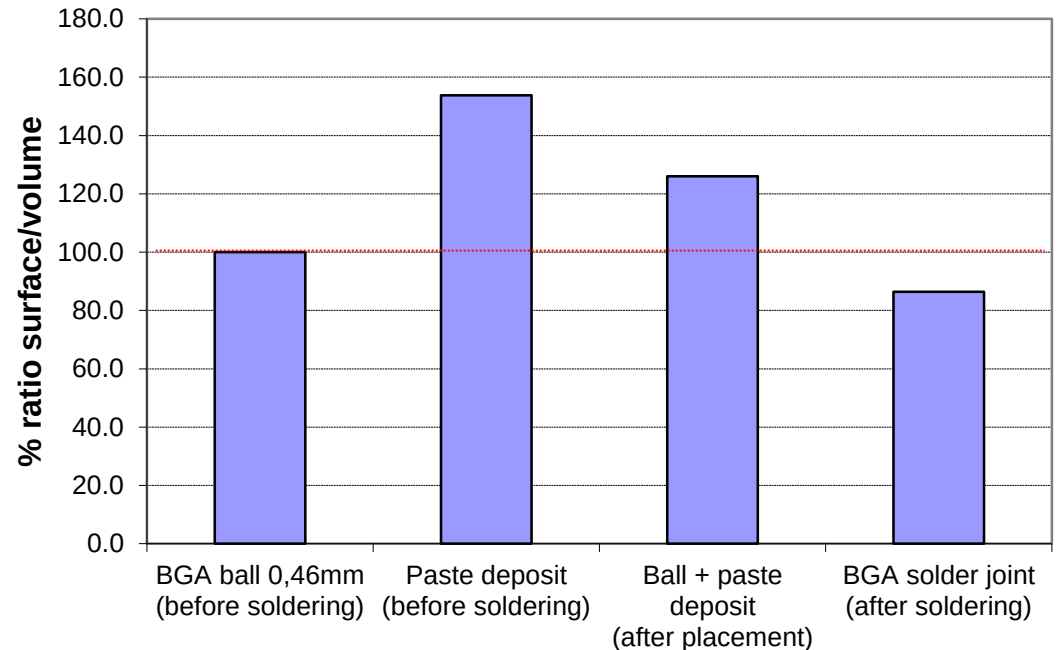
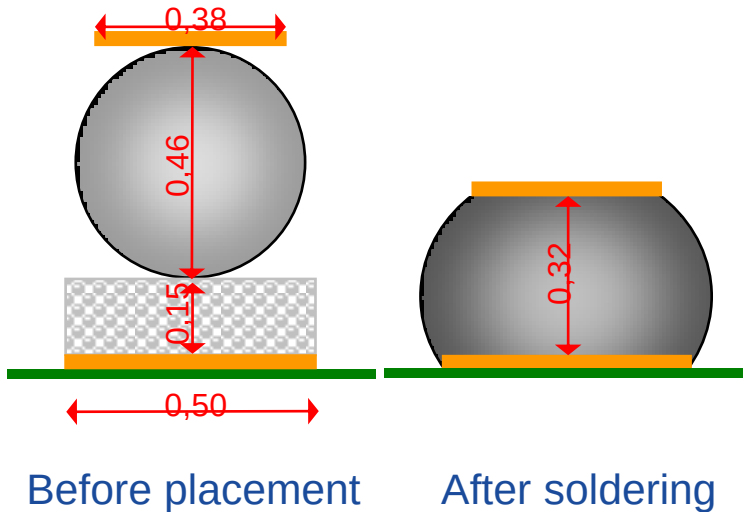


Voiding

■ Influence of geometry

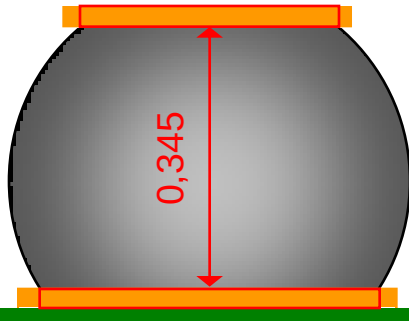
■ BGA solder joint, geometric conditions

Total solder volume: 0,065 mm³

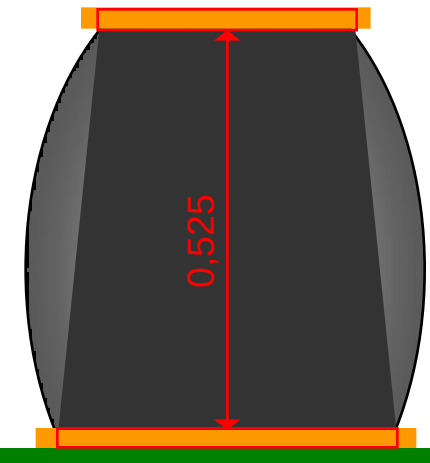
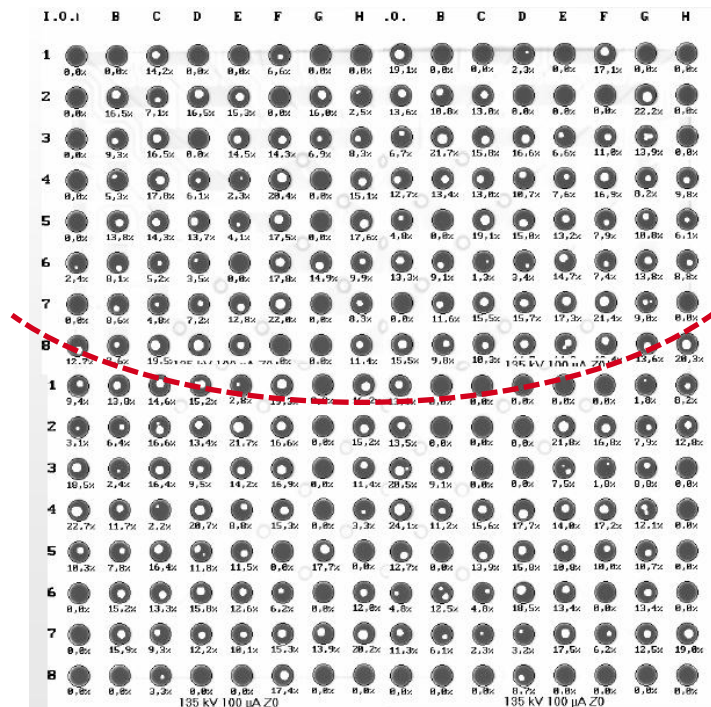


Voiding

- Influence of geometry
 - Twisting/warpage of BGA solder joints



After ball collapse (~ 110 μm)

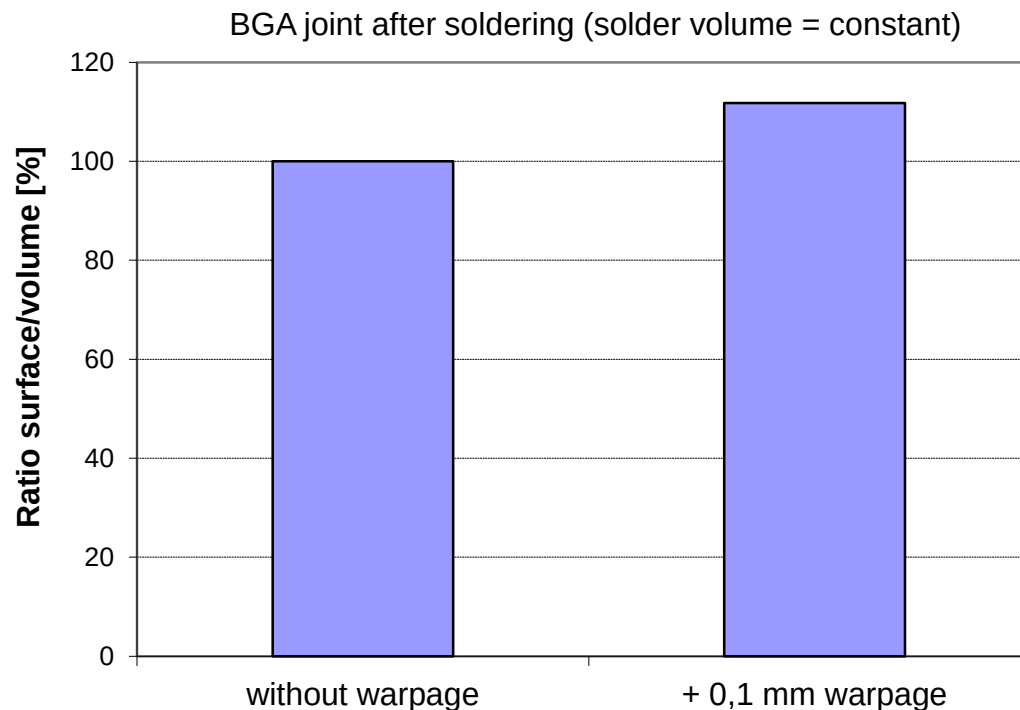


After warpage of 180 μm

Voiding

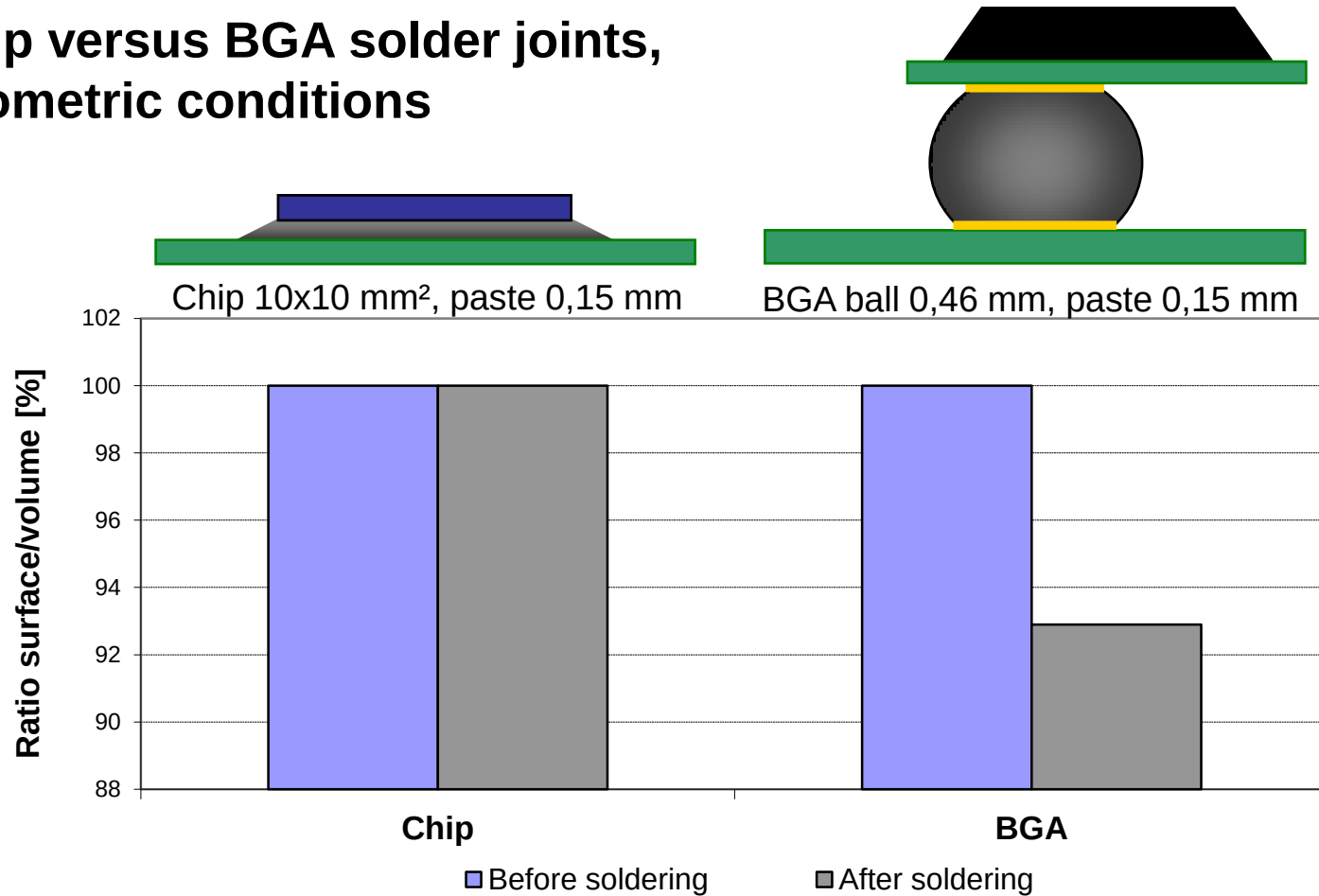
■ Influence of geometry

- Twisting/warpage of BGA solder joints



Voiding

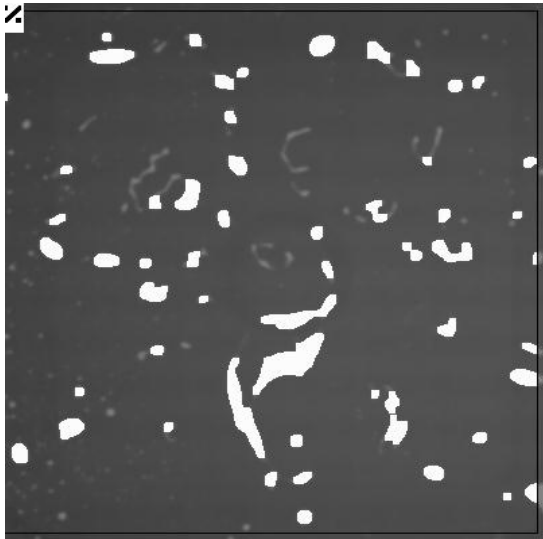
■ Chip versus BGA solder joints, geometric conditions



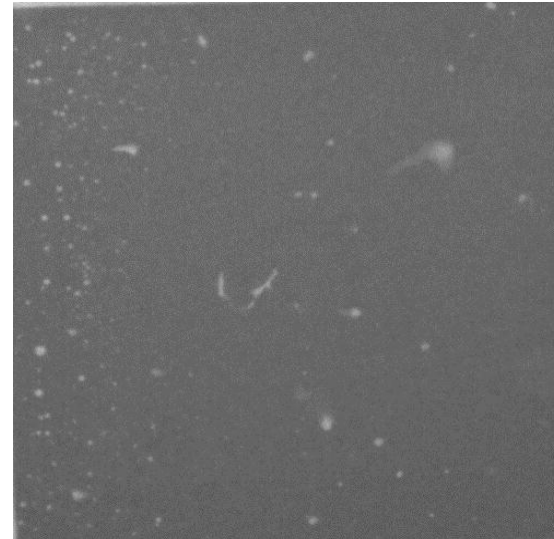
Voiding

■ Influence of of gap thickness (solder paste thickness)

- Si-Chip, paste: SnAgCu, vacuum condensation soldering



Paste thickness: 125 µm



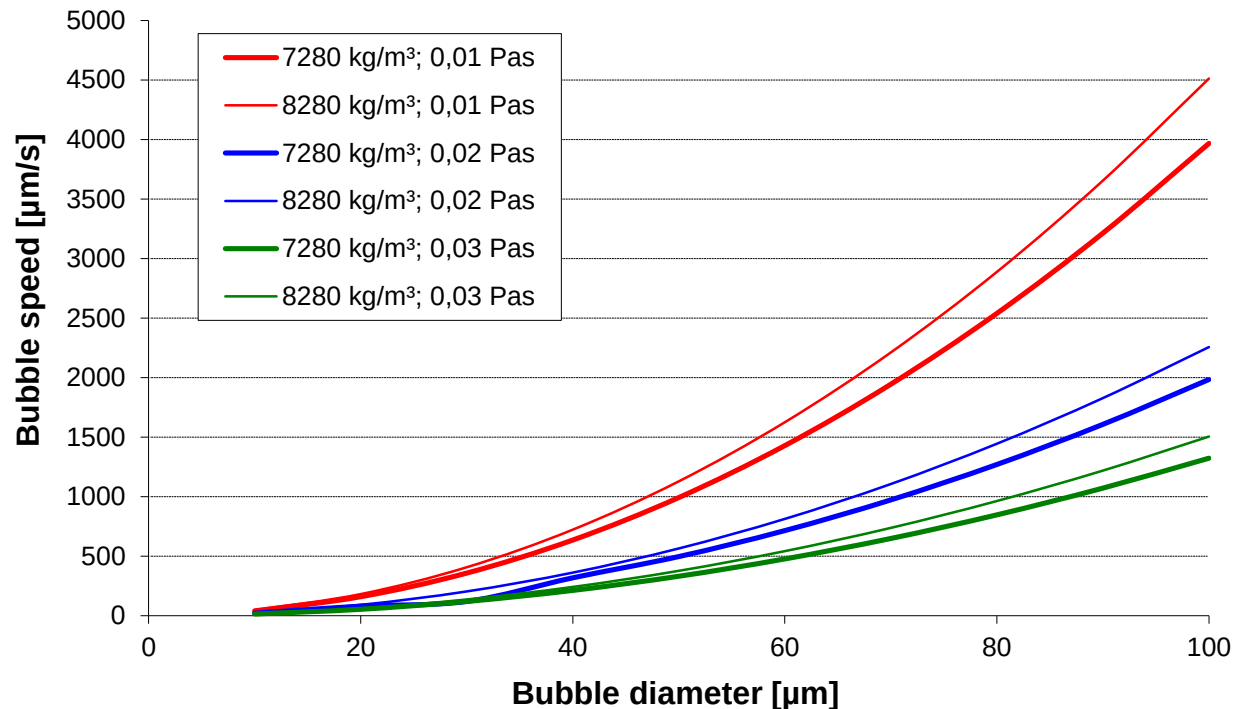
Paste thickness: 180 µm

Voiding

■ Bubbles' rate of ascent

- Calculated according to viscosity data from Fraunhofer IZM Berlin

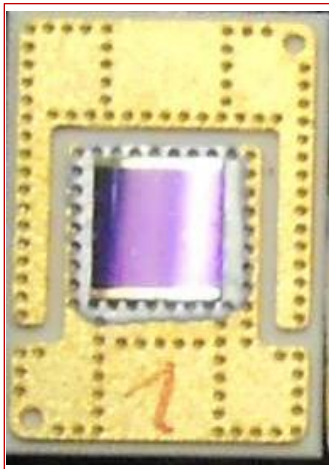
$$v_B = \frac{1}{18} \cdot \frac{(\rho_B - \rho_L) \cdot d^2 \cdot g}{\eta}$$



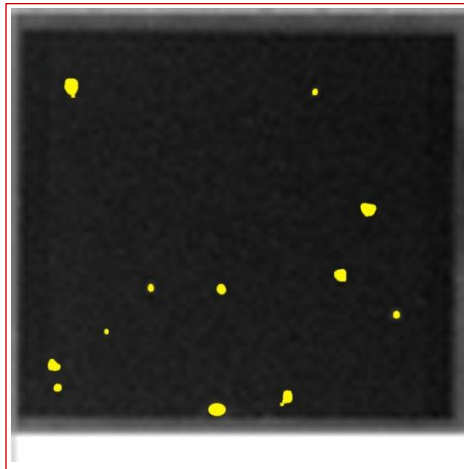
Voiding

■ Influence of vacuum (low pressure level)

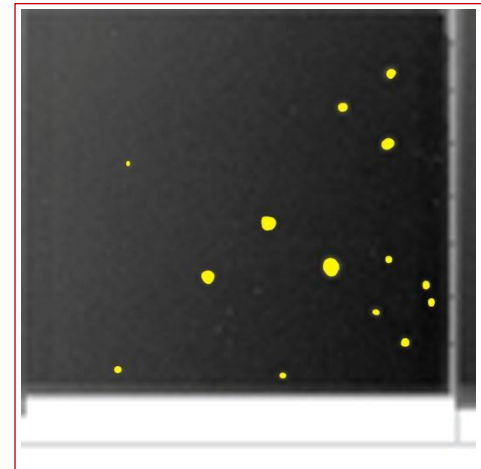
- No significant improvement during longer vacuum dwell time
0,23 % voids



10 mbar @ 10 s



100 mbar @ 100 s



Thank you!

■ Thanks to our colleagues of the working group:

- Dr. Norbert Holle, Robert Bosch GmbH, Schwieberdingen
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